

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10541240	OUCHI, TOSHIHIKO
	Examiner	Art Unit
	RYAN LEPISTO	2883

SEARCHED

Class	Subclass	Date	Examiner
385	4, 8, 12, 40, 41, 45	11/19/08	RAL
359	331, 332	11/19/08	RAL
250	358.1, 393, 227.12	11/19/08	RAL

SEARCH NOTES

Search Notes	Date	Examiner
See search history - EAST (all databases), non-patent literature (IEEE, OpticsInfoBase)	11/19/08	RAL

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner